7/14/2016

RELIABILITY MONITOR REPORT
FOR

San Antonio 0.8µm Silicon Gate CMOS EEPROM (EB8)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX16047ETN+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 9302 QUANTITY: 48 FAILS: 0 FITS: 12.3

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2016 and 6/30/2016 .

Process Information:

Process Description: San Antonio 0.8µm Silicon Gate CMOS EEPROM (EB8)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1535	MAX16047ETN+	135°C	1000 HRS	48	0	TFDZCA117AB
				Total:		**0**	

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